# DMN3404L

### **Product Summary**

TY Semicondutor<sup>®</sup>

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> max	l <sub>D</sub> max T <sub>A</sub> = +25°C
30V	28mΩ @ V <sub>GS</sub> = 10V	5.8A
	42mΩ @ V <sub>GS</sub> = 4.5V	4.8A
	82mΩ @ V <sub>GS</sub> = 3V	2.0A

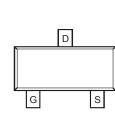
## Description

This MOSFET has been designed to minimize the on-state resistance (R<sub>DS(ON)</sub>) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

## Applications

- **Battery Charging**
- **Power Management Functions**
- **DC-DC Converters**
- Portable Power Adaptors





Top View

Top View

## Ordering Information (Note 4 & 5)

Part Number	Compliance	Case	Packaging
DMN3404L-7	Standard	SOT23	3000/Tape & Reel
DMN3404LQ-7	Automotive	SOT23	3000/Tape & Reel

O Source

Internal Schematic

Drain

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.

2. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

## **Marking Information**

Notes:

34N	ΥM	34N = Pro YM = Dat Y = Year M = Mont

oduct Type Marking Code

te Code Marking

(ex: W = 2009)

th (ex: 9 = September)

#### Date Code Key 2010 2011 2014 2009 2012 2013 2015 Year W Code Х Y В С 7 А Month Jan Feb Mar May Jun Jul Sep Oct Nov Dec Apr Aug Code 1 2 3 4 5 6 7 8 9 0 Ν D

# N-CHANNEL ENHANCEMENT MODE MOSFET

# Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free & Fully RoHS compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

### **Mechanical Data**

- Case: SOT23
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208 (3)
- Terminals Connections: See Diagram Below
- Weight: 0.008 grams (approximate)



#### **Product specification**

# DMN3404L

# Maximum Ratings (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic Drain-Source Voltage (Note 6 & 7) Gate-Source Voltage			Symbol VDSS	Value 30	Units V
			VGSS	±20	V
Continuous Drain Current (Note 6) V <sub>GS</sub> = 10V	Steady State	T <sub>A</sub> = -40°C T <sub>A</sub> = +25°C T <sub>A</sub> = +85°C	Ι <sub>D</sub>	4.6 4.2 3.0	A
Continuous Drain Current (Note 7) V <sub>GS</sub> = 10V	Steady State	T <sub>A</sub> = -40°C T <sub>A</sub> = +25°C T <sub>A</sub> = +85°C	ID	6.2 5.8 4.0	А
Continuous Drain Current (Note 7) V <sub>GS</sub> = 4.5V	Steady State	T <sub>A</sub> = -40°C T <sub>A</sub> = +25°C T <sub>A</sub> = +85°C	ID	5.2 4.8 3.2	A
Continuous Drain Current (Note 7) V <sub>GS</sub> = 3V	Steady State	T <sub>A</sub> = -40°C T <sub>A</sub> = +25°C T <sub>A</sub> = +85°C	ID	2.2 2.0 1.0	A
Pulsed Drain Current			I <sub>DM</sub>	30	А

# **Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 6)	PD	0.72	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = +25°C	R <sub>0JA</sub>	173	°C/W
Power Dissipation (Note 7)	PD	1.4	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = +25°C	R <sub>0JA</sub>	90	°C/W
Operating and Storage Temperature Range	T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

Notes:

Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.



#### **Product specification**

# DMN3404L

Electrical Characteristics (@T <sub>A</sub> = +25°C, unless otherwise specified.)							
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)						·	
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30		_	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	_		1.0	μA	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_		±100	nA	$V_{GS}$ = ±20V, $V_{DS}$ = 0V	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	1.5	2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance $T_1 = -40^{\circ}C$ (Note 9)	<b>D</b>	—	23	27	_	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 4.8A	
Static Drain-Source On-Resistance 1 J = -40 C (Note 9)	R <sub>DS(ON)</sub>	—	57	74	—	V <sub>GS</sub> =3V, I <sub>D</sub> =2A	
		_	24	28		V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.8A	
Static Drain-Source On-Resistance $T_J = +25^{\circ}C$	R <sub>DS(ON)</sub>	—	33	42	mΩ	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 4.8A	
		_	63	82		V <sub>GS</sub> =3V, I <sub>D</sub> =2A	
Static Drain-Source On-Resistance T <sub>J</sub> = +85°C (Note 9)	R <sub>DS(ON)</sub>	_	71	95	mΩ	V <sub>GS</sub> =3V, I <sub>D</sub> =2A	
Forward Transfer Admittance	Y <sub>fs</sub>	_	10	_	S	V <sub>DS</sub> = 5V, I <sub>D</sub> = 5.8A	
Diode Forward Voltage	V <sub>SD</sub>	_	0.75	1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1A	
DYNAMIC CHARACTERISTICS (Note 10)							
Input Capacitance	Ciss	_	498	_	pF		
Output Capacitance	Coss	_	52	_	pF	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Reverse Transfer Capacitance	Crss	_	45	_	pF		
Gate Resistance	Rg	—	1.75	2.8	Ω	$V_{DS}$ = 0V, $V_{GS}$ = 0V, f = 1MHz	
Total Gate Charge (V <sub>GS</sub> = 3V)	Qg		3.8	5.3	nC	V <sub>GS</sub> = 3V, V <sub>DS</sub> = 15V, I <sub>D</sub> = 1A	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	—	5.3	7.5	nC		
Total Gate Charge (V <sub>GS</sub> = 10V)	Qg	—	11.3	16	nC	V <sub>GS</sub> = 10V/4.5V, V <sub>DS</sub> = 15V,	
Gate-Source Charge	Q <sub>gs</sub>	—	1.4		nC	I <sub>D</sub> = 5.8A	
Gate-Drain Charge	Q <sub>gd</sub>	—	2.1		nC		
Turn-On Delay Time	t <sub>D(on)</sub>	—	3.41	10	ns		
Turn-On Rise Time	tr	_	6.18	13	ns	V <sub>DD</sub> = 15V, V <sub>GS</sub> = 10V,	
Turn-Off Delay Time	t <sub>D(off)</sub>	—	13.92	28	ns	$R_L$ = 2.6 $\Omega$ , $R_G$ = 3 $\Omega$	
Turn-Off Fall Time	t <sub>f</sub>	_	2.84	10	ns		

Notes:

Short duration pulse test used to minimize self-heating effect.
Guaranteed by design and 25°C data. Not subject to production testing
Guaranteed by design. Not subject to production testing.